Test Report

Report No.: SZPR101025117703E

Client : Samtec Electronics (HuiZhou) Limited

Address : Huangxi Industrial Park, Shiwan Town, Boluo County, Huizhou City, Guangdong Province, China

Report on the submitted sample said to be:

Sample Name	: Connector
Sample Description	: Normal
Model/type	: NR-PCIE-164-02-L-D-RA
Amount of Sample	: 12 pcs
Sample Received Date	: Oct. 26, 2010
Sample tested Date	: Oct. 31, 2010~ Nov. 03, 2010

Test Requested: (Please see page 2.)

Group	Test Sequence	Test Item
Seq. (c) (001~008)	1	Low Level Contact Resistance (LLCR)
	2	Mechanical Shock Test
	3	Low Level Contact Resistance (LLCR)
	4	Random Vibration Test
	5	Low Level Contact Resistance (LLCR)
Seq. (d) (009~012)	1	Mechanical Shock Test
	2	Random Vibration Test

Test Results: Please see the attached sheets.

Inspected by: Tim Sun Engineer

Approved by: Roger Diao Lab Supervisor

Approved date: Nov. 10, 2010

CENTRE TESTING INTERNATIONAL SZ11 CTI

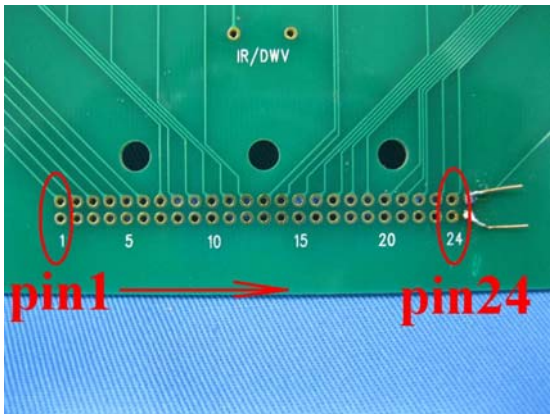
Data Summary:

Group	Test Sequence	Test Item	Requirement	Result
Seq. (c) (001~008)	1	Low Level Contact Resistance (LLCR)	△R≤10 mΩ No damage	Pass
	2	Mechanical Shock Test		
	3	Low Level Contact Resistance (LLCR)		
	4	Random Vibration Test	△R≤10 mΩ No damage	Pass
	5	Low Level Contact Resistance (LLCR)		
Seq. (d) (009~012)	1	Mechanical Shock Test	No damage	Pass
			0.1 microsecond	Pass
	2	Random Vibration Test	No damage	Pass
			1 microsecond	Pass

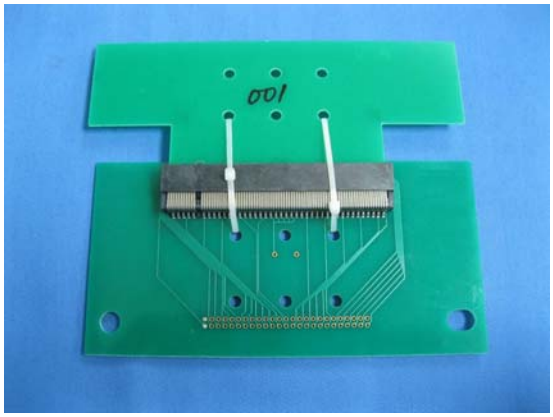
Tested Samples:

Test Seq.	Sample No.	Sample Name	Model/type	Quantity
Seq. (c)	001~008	Connector	NR-PCIE-164-02-L-D-RA	8 pcs
Seq. (d)	009~012	Connector	NR-PCIE-164-02-L-D-RA	4 pcs

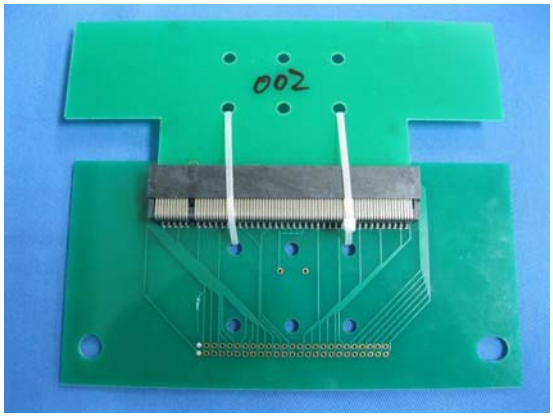
Pin No. of Sample:



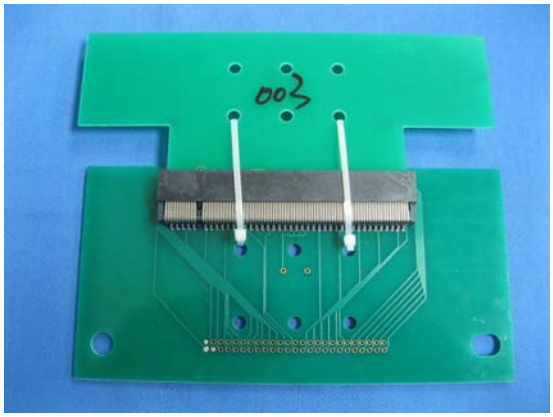
Sample Photos before the Test:



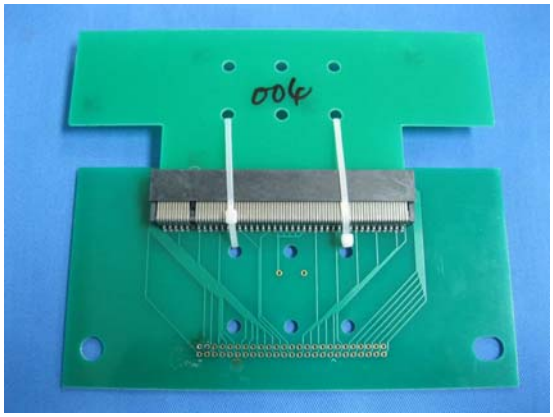
001



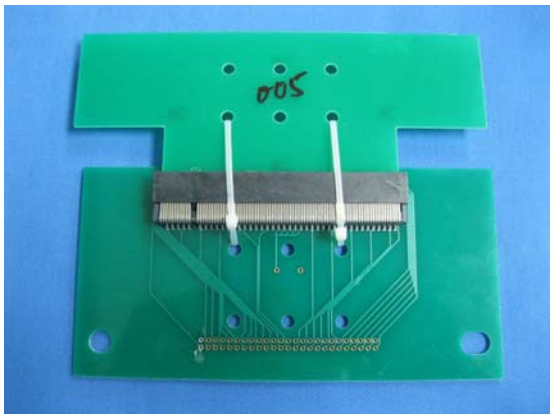
002



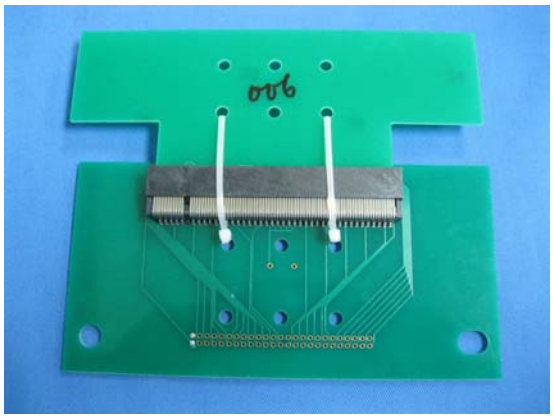
003



004

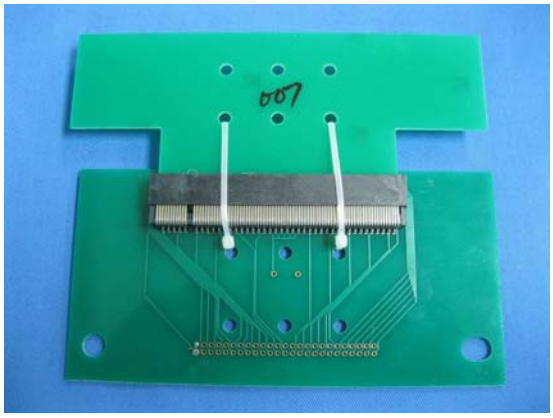


005

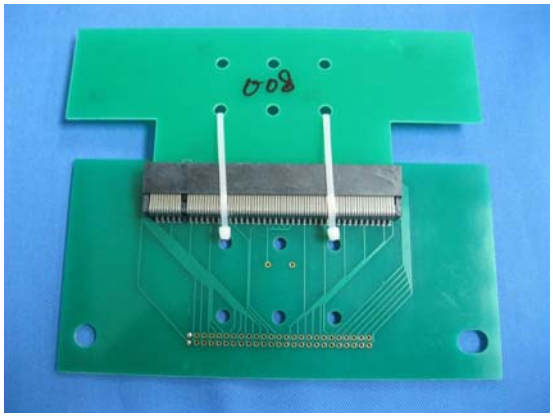


006

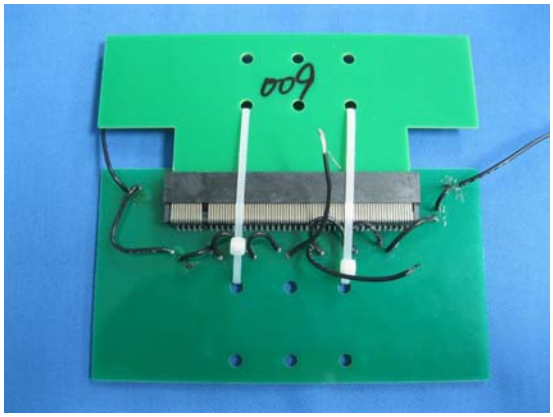
Sample Photos before the Test:



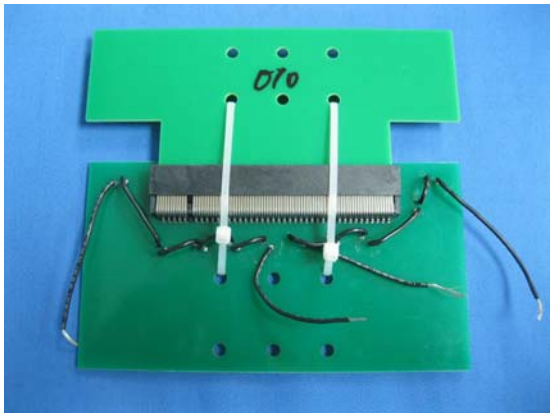
007



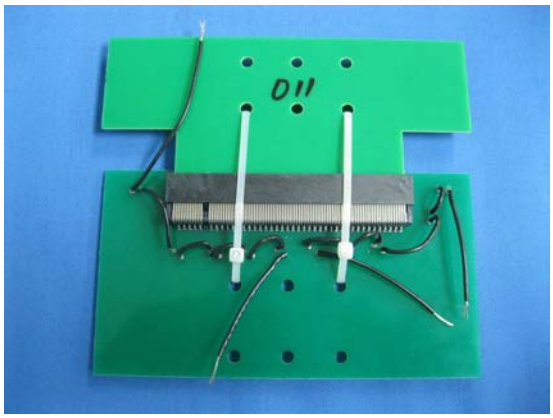
008



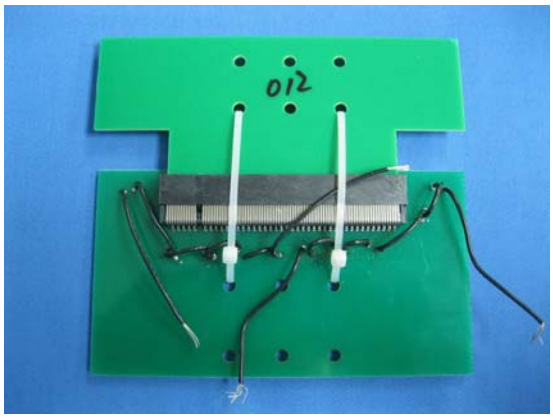
009



010



011



012

Test Seq. (c)

Test Item 1: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Milliohmmeter	Agilent 4338B	BTTEELSZ20034	Feb. 03, 2011

(2) Environmental Conditions:

Temperature: 26℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-23C-2006

(4) Tested Samples: PR101025117703-(001~008)

(5) Test Condition:

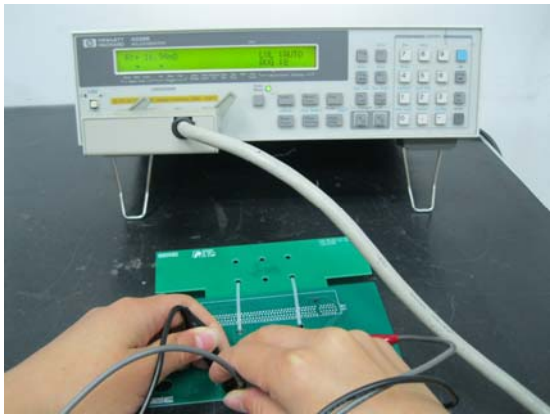
The test performed in accordance to the criteria listed above, and under the conditions as below:

---Test Current: 10 milliamps max

---Measure and record the Low Level Contact Resistance

Test Results: Please see the appendixes from page 37 to page 44.

Test Photo:



LLCR test

Test Seq. (c)

Test Item 2: Mechanical Shock Test

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Mechanical Shock Test System	DP-1200-45	BTTEELSZ20033	May 24, 2011

(2) Environmental Conditions:

Temperature: 26℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-27B-1996

(4) Tested Samples: PR101025117703-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

---Wave form: Half-sine

---Acceleration: 100 g_n

--- Pulse duration: 6 ms

---Direction: Axis ±X, ±Y, ±Z

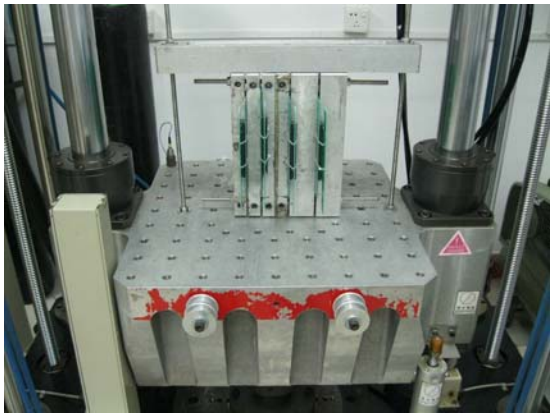
---Number of shocks: 3 shocks /axis, 18 times in total

(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples.

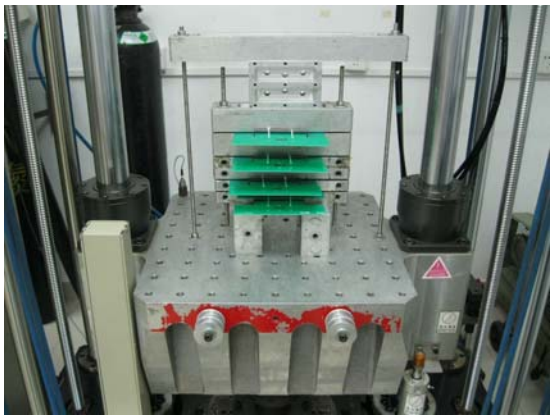
Test Results: There was no evidence of physical damage to the tested samples after the test.

Test Photos:

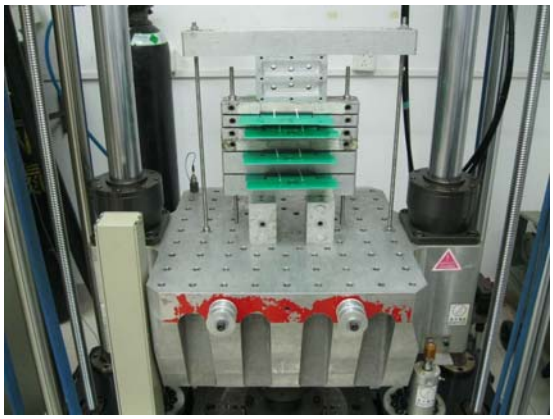


Axis +X

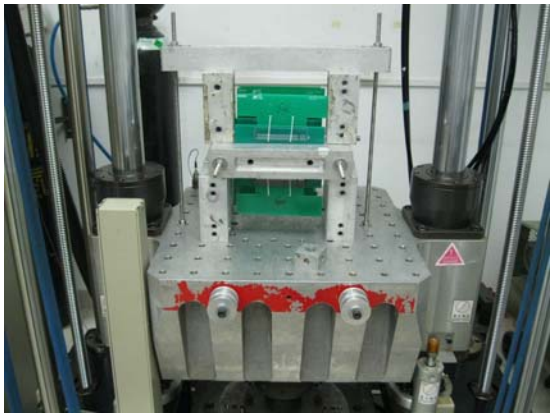
Axis -X



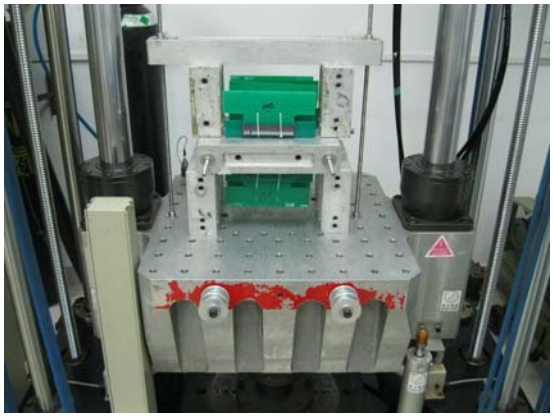
Axis +Y



Axis -Y

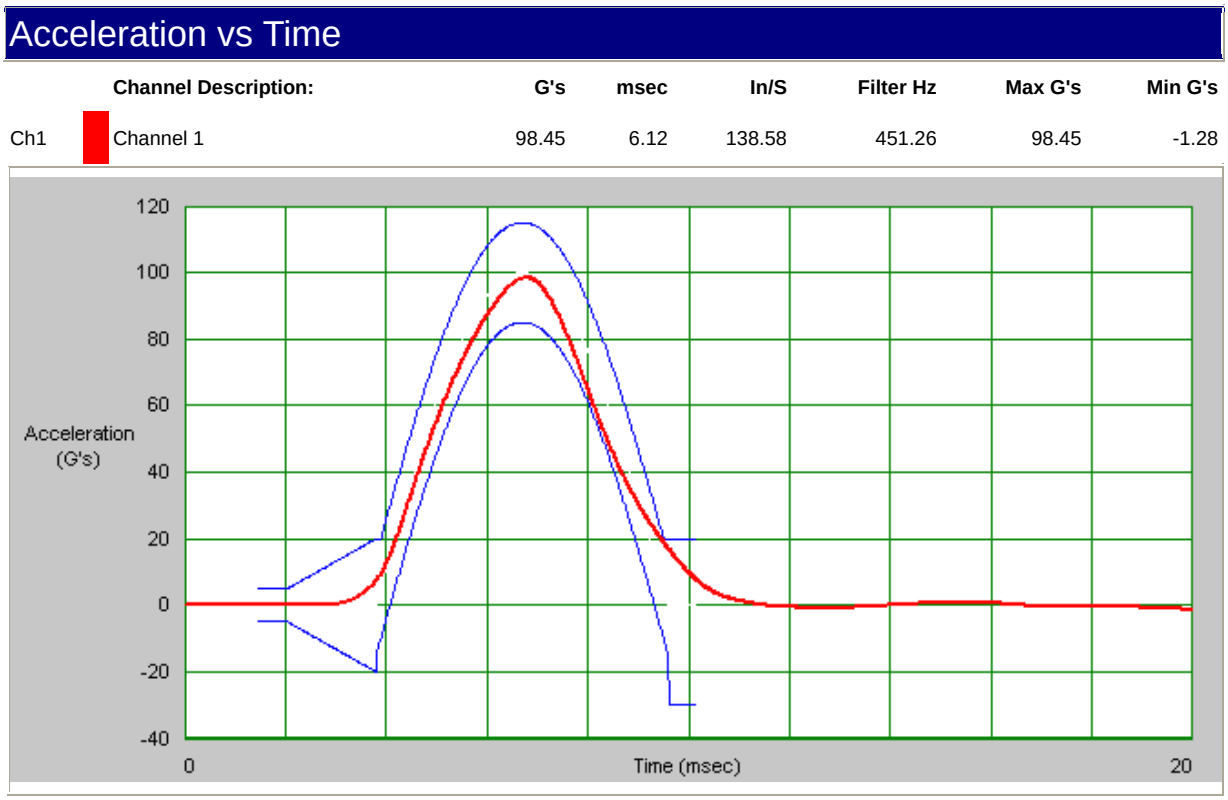


Axis +Z



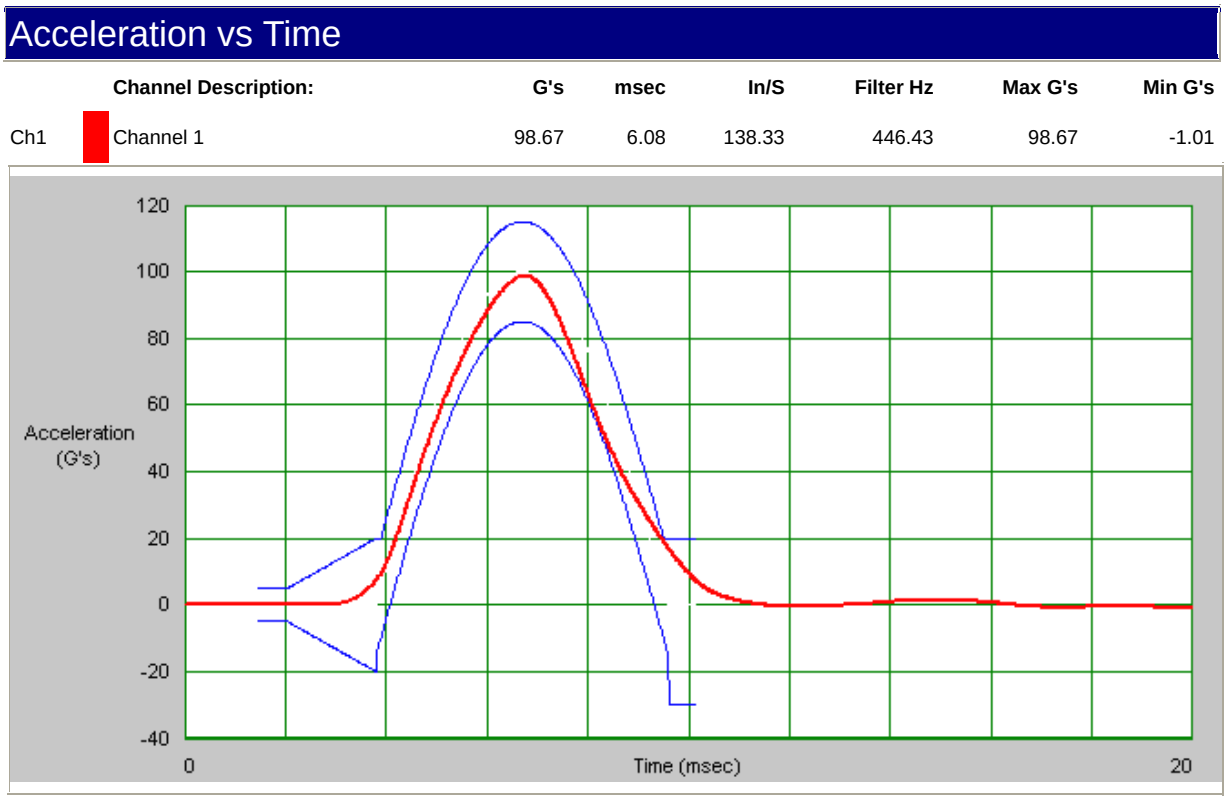
Axis -Z

Test Curve:



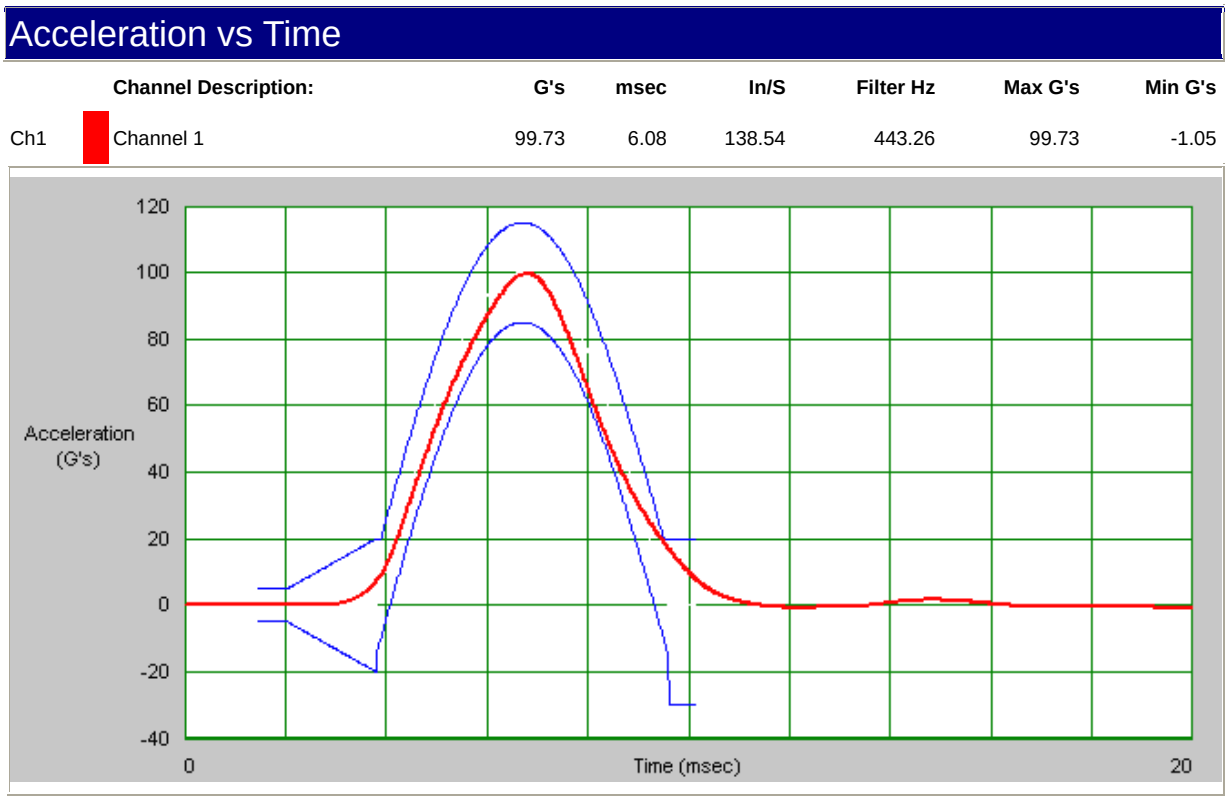
Axis +X

Test Curve:



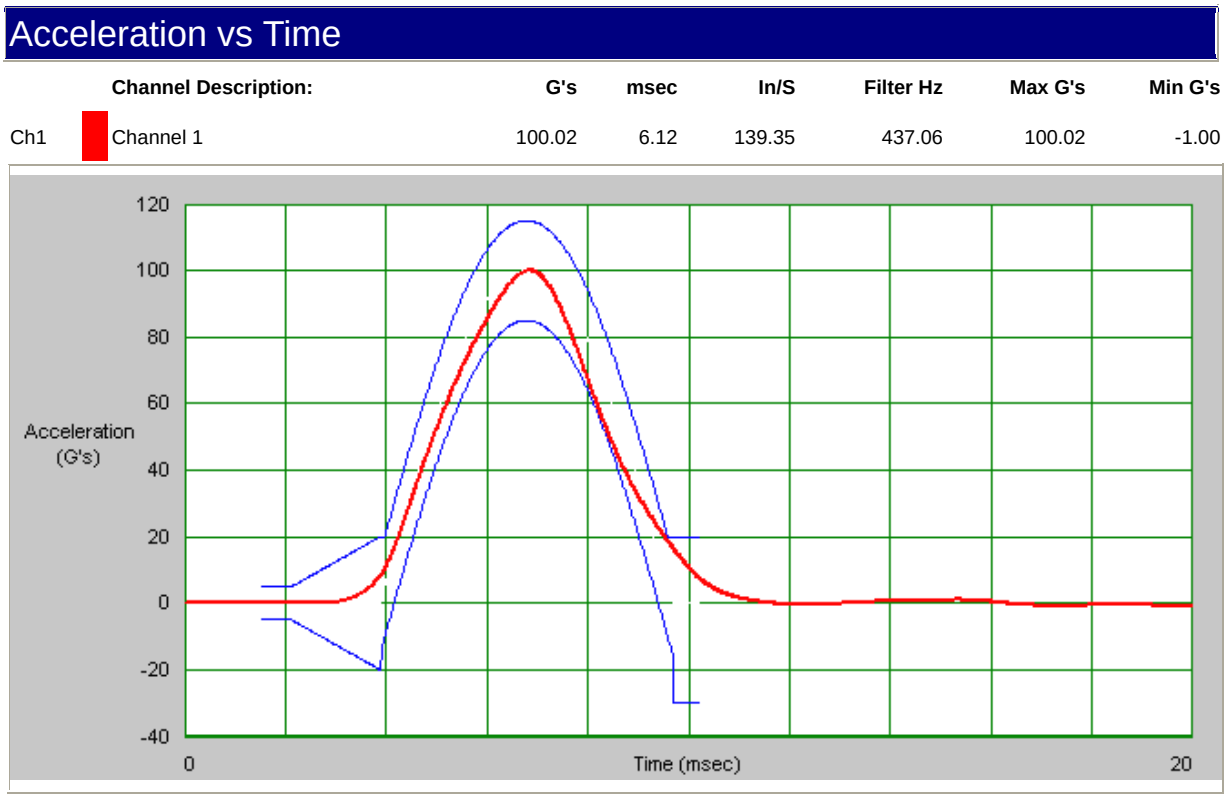
Axis -X

Test Curve:



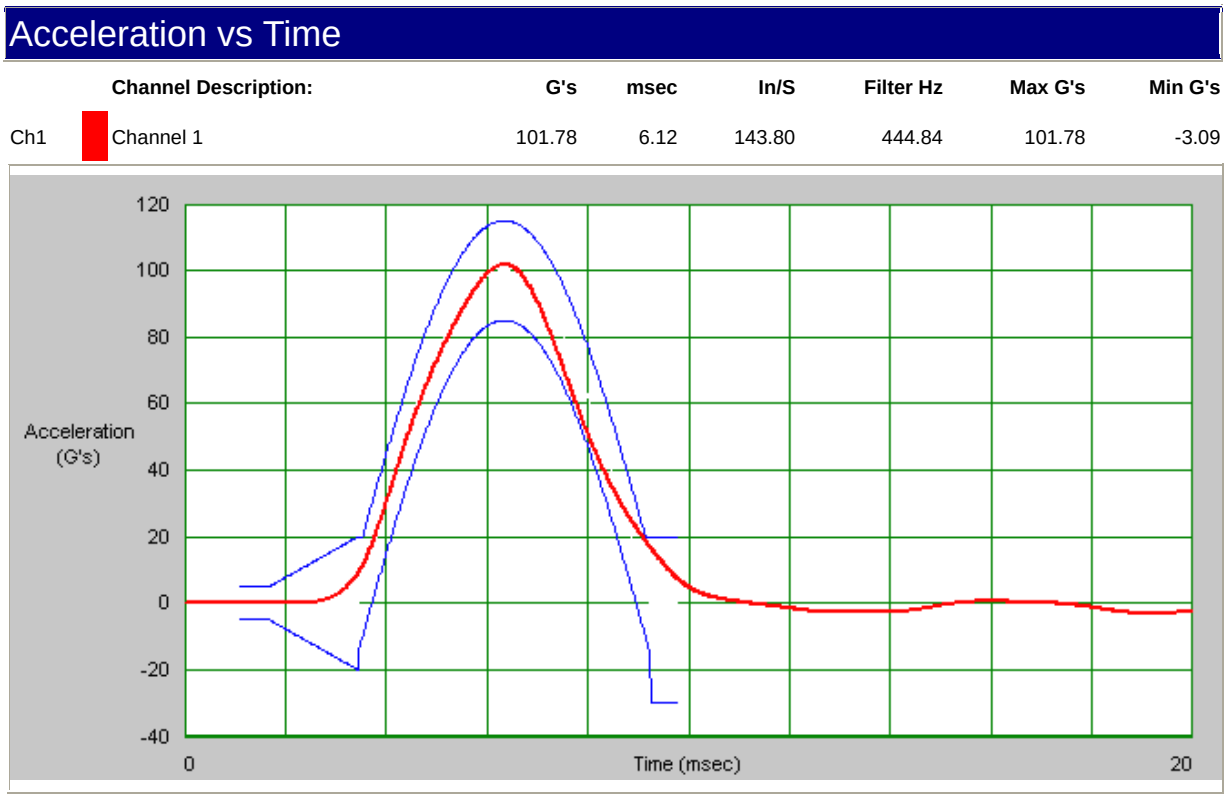
Axis +Y

Test Curve:



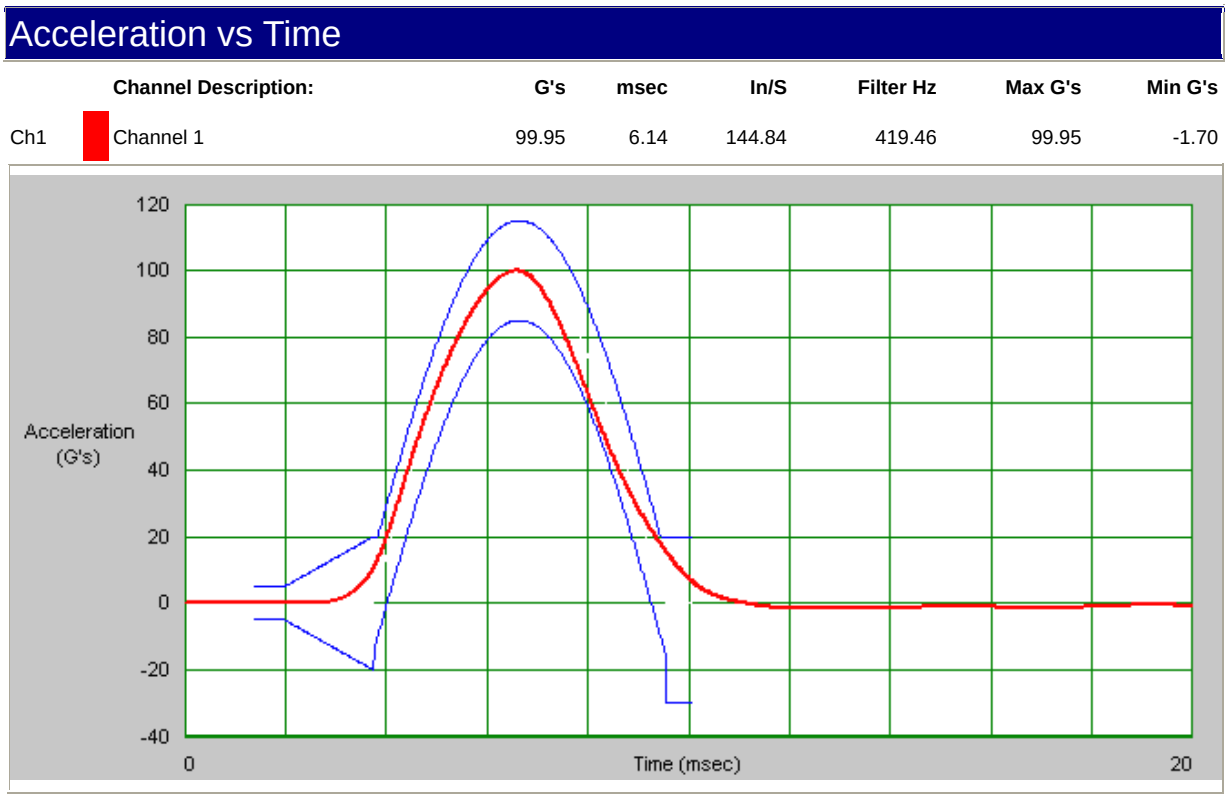
Axis -Y

Test Curve:



Axis +Z

Test Curve:



Axis -Z

Test Seq. (c)

Test Item 3: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Milliohmmeter	Agilent 4338B	BTTEELSZ20034	Feb. 03, 2011

(2) Environmental Conditions:

Temperature: 26℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-23C-2006

(4) Tested Samples: PR101025117703-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

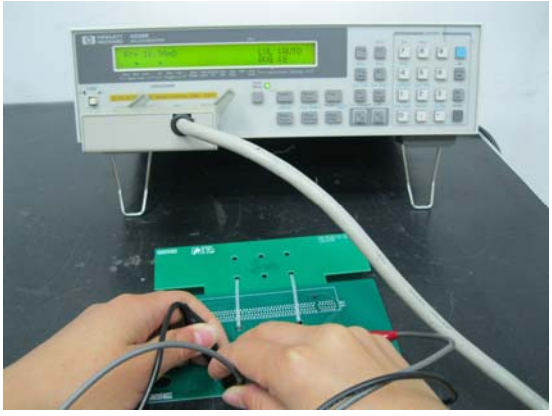
---Test Current: 10 milliamps max

--- Measure and record the Low Level Contact Resistance

---△R≤10 mΩ

Test Results: Please see the appendixes from page 37 to page 44.

Test Photo:



LLCR test

Test Seq. (c):

Test Item 4: Random Vibration Test

(1) Test Equipment:

Name	Model	Serial No.	Valid Date to
Vibration Test System	LDS V850-440-LPT 750	ATTEELSZ20020	Mar. 18, 2011

(2) Environmental Conditions:

Temperature: 24℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-28E-2006

(4) Tested Samples: PR101025117703-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

Frequency (Hz)	PSD (g^2/ Hz)	Slope (dB/oct)
50	/	+6
100-1000	0.04	/
2000	/	-6

---Acceleration: 7.56Grms

---Direction: Axis X, Y, Z

---Test duration: 2hours/axis

(6) Acceptance criteria:

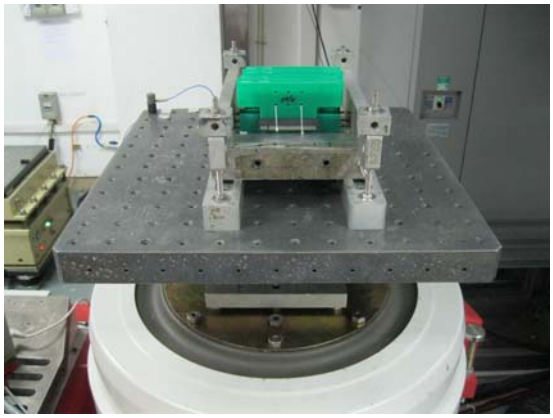
---There shall be no evidence of physical damage to the tested samples.

Test Results: There was no evidence of physical damage to the tested samples after the test.

Test Photos:

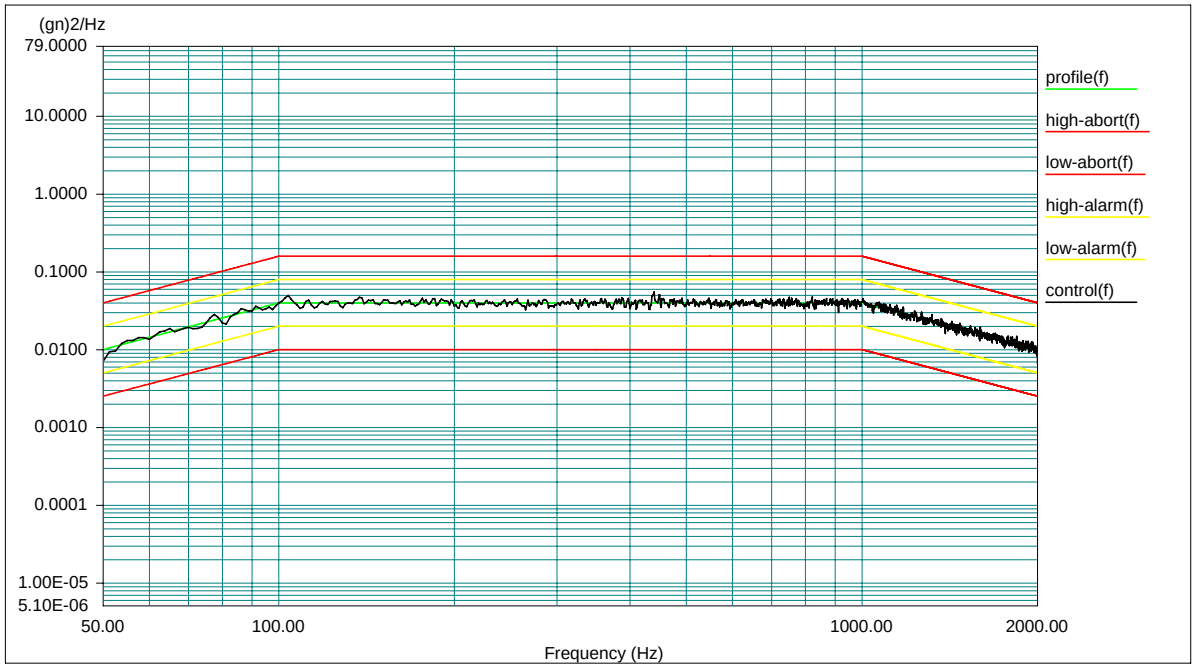
Axis X

Axis Y



Axis Z

Test Curve:



Level: 100 %

Control RMS: 7.576784 gn Full Level Elapsed Time: 02:00:00 Lines: 1600 Frame Time: 0.800000 Seconds

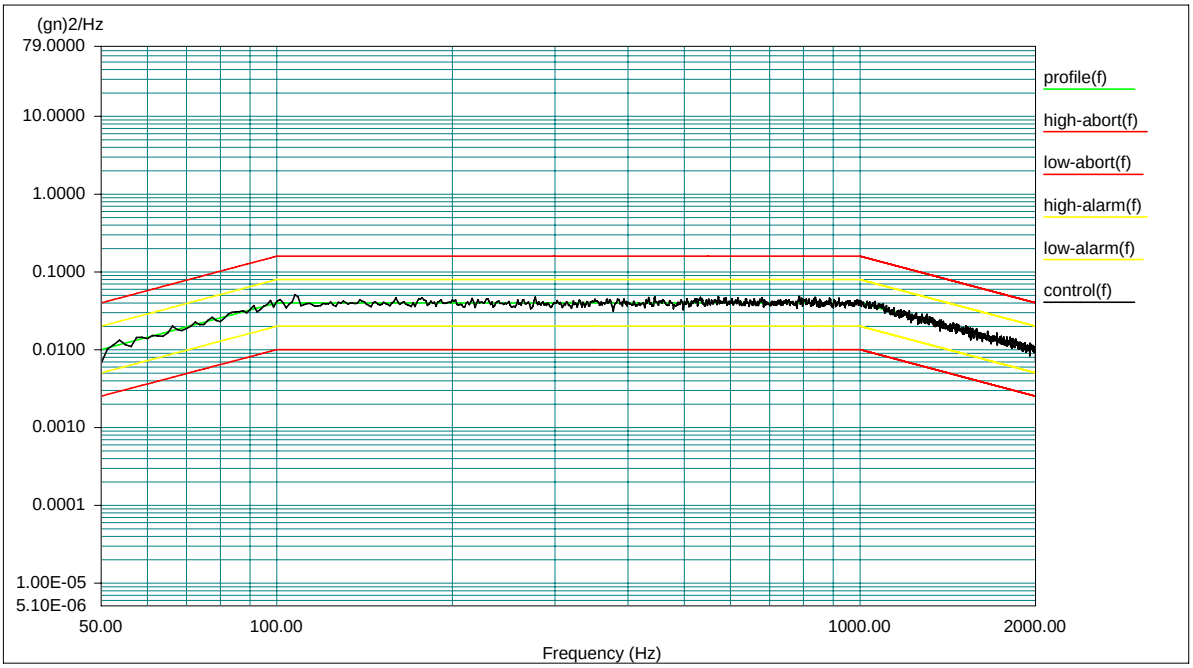
Demand RMS: 7.564273 gn Remaining Time: 00:00:00 DOF: 154 dF: 1.250000 Hz

Data saved at 08:06:59 PM, Saturday, October 30, 2010

Report created at 08:07:00 PM, Saturday, October 30, 2010

Axis X

Test Curve:



Level: 100 %

Control RMS: 7.572187 gn Full Level Elapsed Time: 02:00:04 Lines: 1600 Frame Time: 0.800000 Seconds

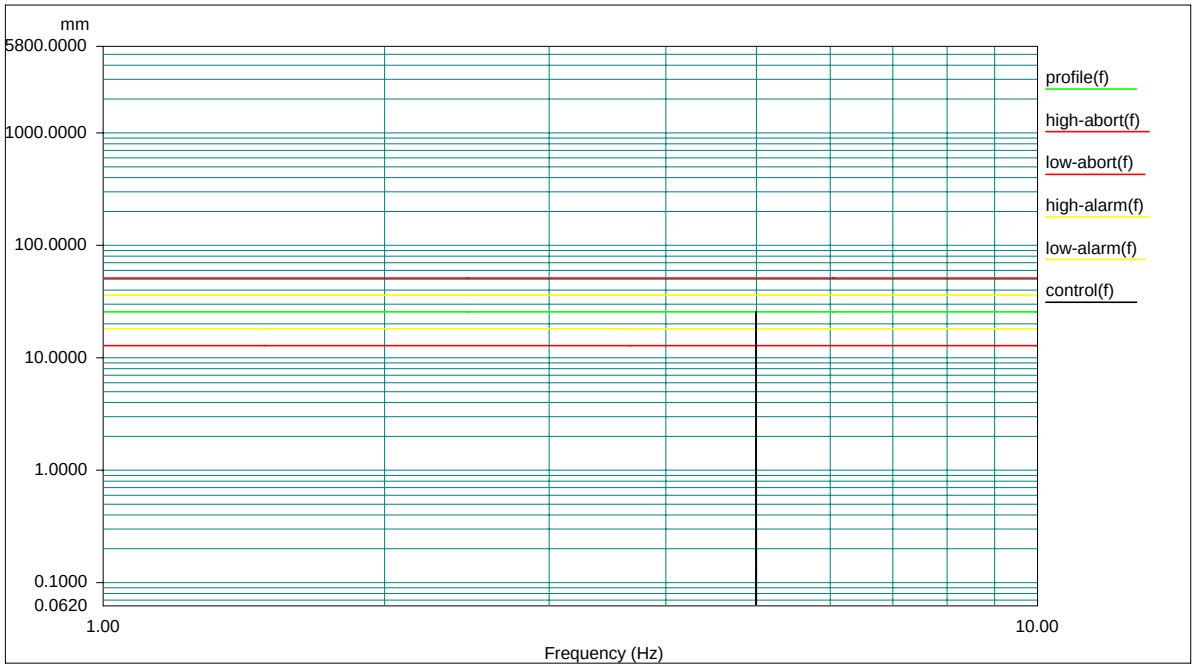
Demand RMS: 7.564273 gn Remaining Time: 00:00:00 DOF: 154 dF: 1.250000 Hz

Data saved at 05:03:06 PM, Saturday, October 30, 2010

Report created at 05:03:18 PM, Saturday, October 30, 2010

Axis Y

Test Curve:



Level:	100 %	Full Level Time:	00:47:22	Sweep Type:	Logarithmic
Frequency:	5.000000 Hz	Time Remaining:	00:00:00	Sweep Rate:	1 Oct/Min

Data saved at 10:32:54 PM, Tuesday, September 28, 2010

Report created at 10:32:56 PM, Tuesday, September 28, 2010

Axis Z

Test Seq. (c):

Test Item 5: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Milliohmmeter	Agilent 4338B	BTTEELSZ20034	Feb. 03, 2011

(2) Environmental Conditions:

Temperature: 24℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-23C-2006

(4) Tested Sample: PR101025117703-(001~008)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

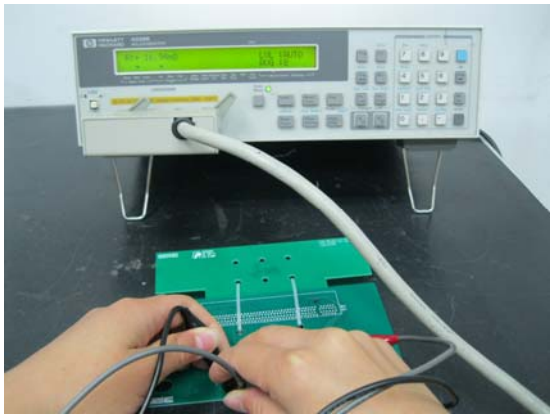
---Test Current: 10 milliamps max

---Measure and record the Low Level Contact Resistance

---△R≤10 mΩ

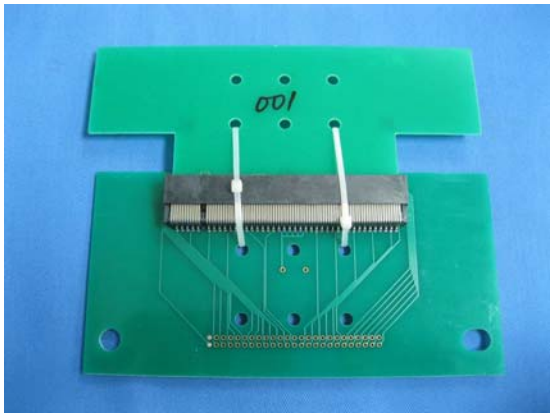
Test Results: Please see the appendixes from page 37 to page 44.

Test Photo:

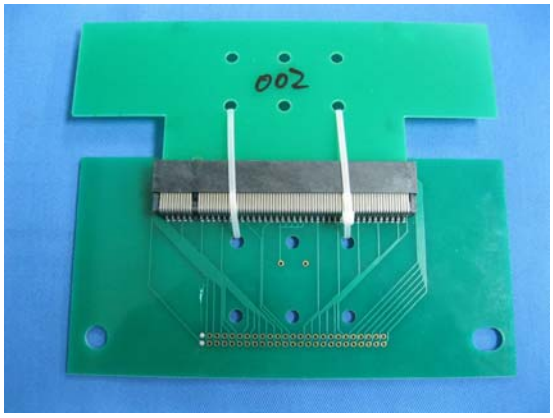


LLCR test

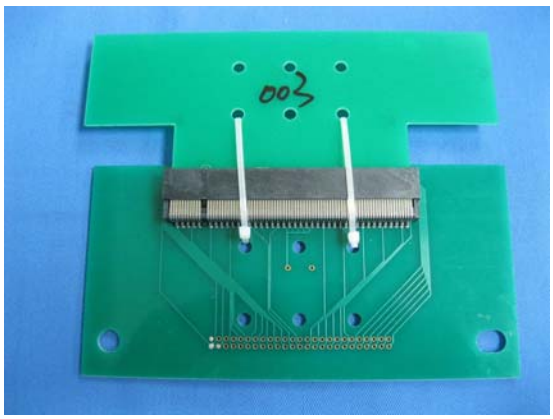
Sample Photos after testing Seq. (c):



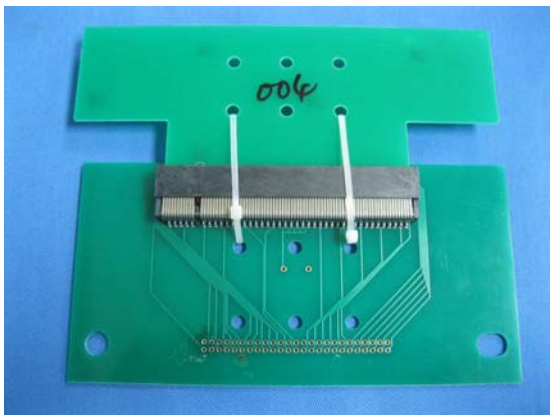
001



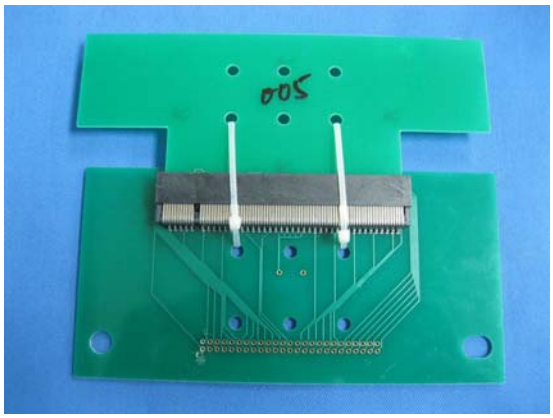
002



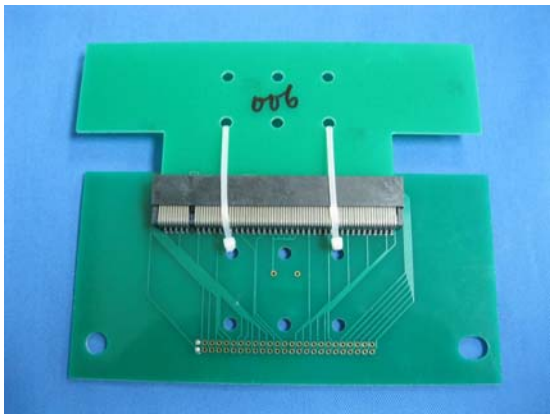
003



004

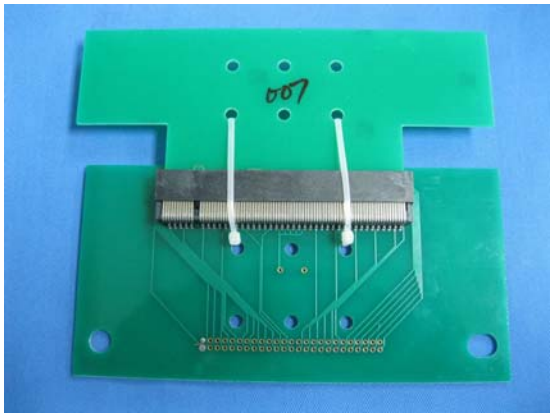


005

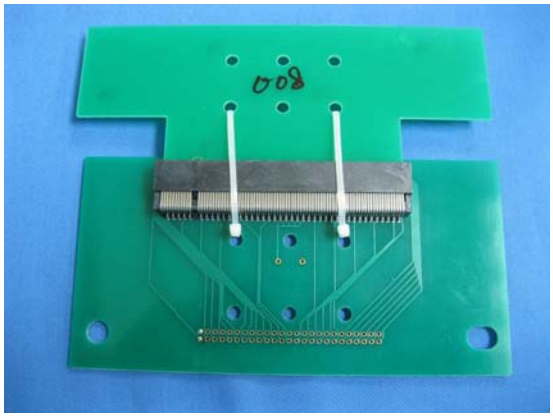


006

Sample Photos after testing Seq. (c):



007



008

Test Seq. (d)

Test Item 1: Mechanical Shock Test

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Mechanical Shock Test System	DP-1200-45	BTTEELSZ20033	May 24, 2011
Instantaneous circuit tester	NM11A	BTTEELSZ20063	Aug. 24, 2011

(2) Environmental Conditions:

Temperature: 26℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-27B-1996

(4) Tested Samples: PR101025117703-(009~012)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

---Wave form: Half-sine

---Acceleration: 100 g_n

--- Pulse duration: 6 ms

---Direction: Axis ±X, ±Y, ±Z

---Number of shocks: 3 shocks /axis, 18 times in total

---Monitor the discontinuity duration of samples during the test

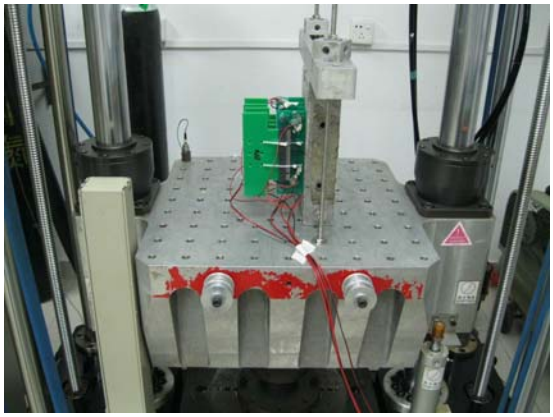
(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples.

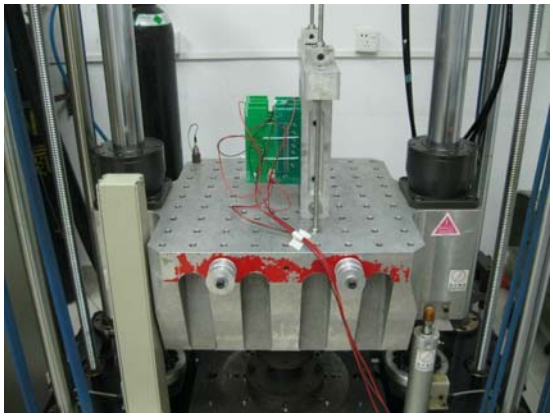
---There shall be no low microsecond event detected greater than 0.1 microsecond.

Test Results: After the test, there was no evidence of physical damage to the tested samples and the low microsecond event detected was never greater than 0.1 microsecond. Other characteristics should be evaluated by the client.

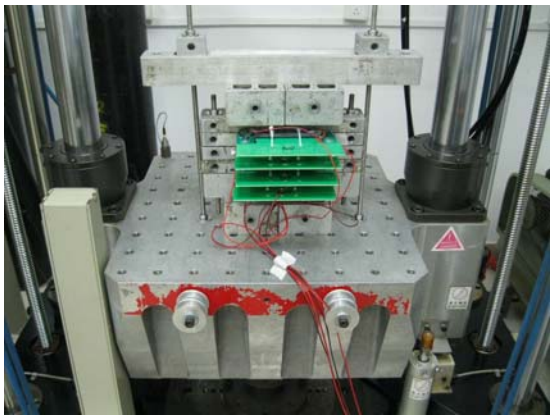
Test Photos:



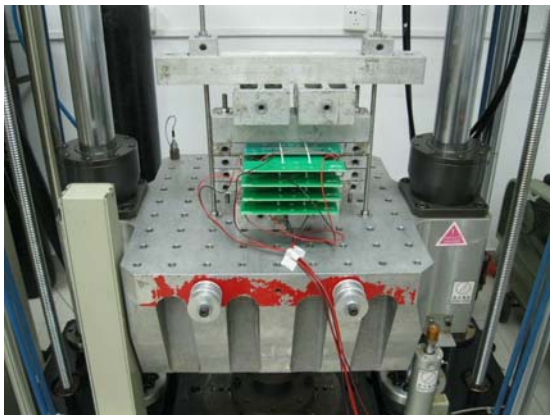
Axis +X



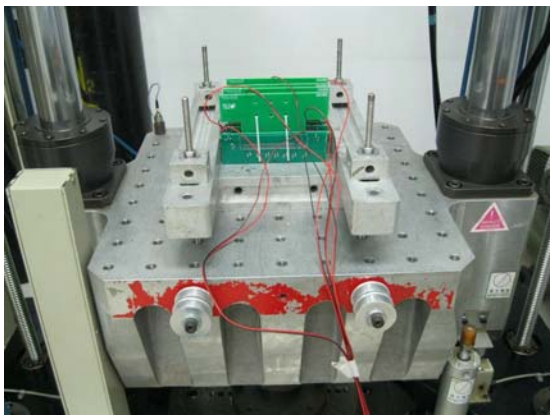
Axis -X



Axis +Y



Axis -Y



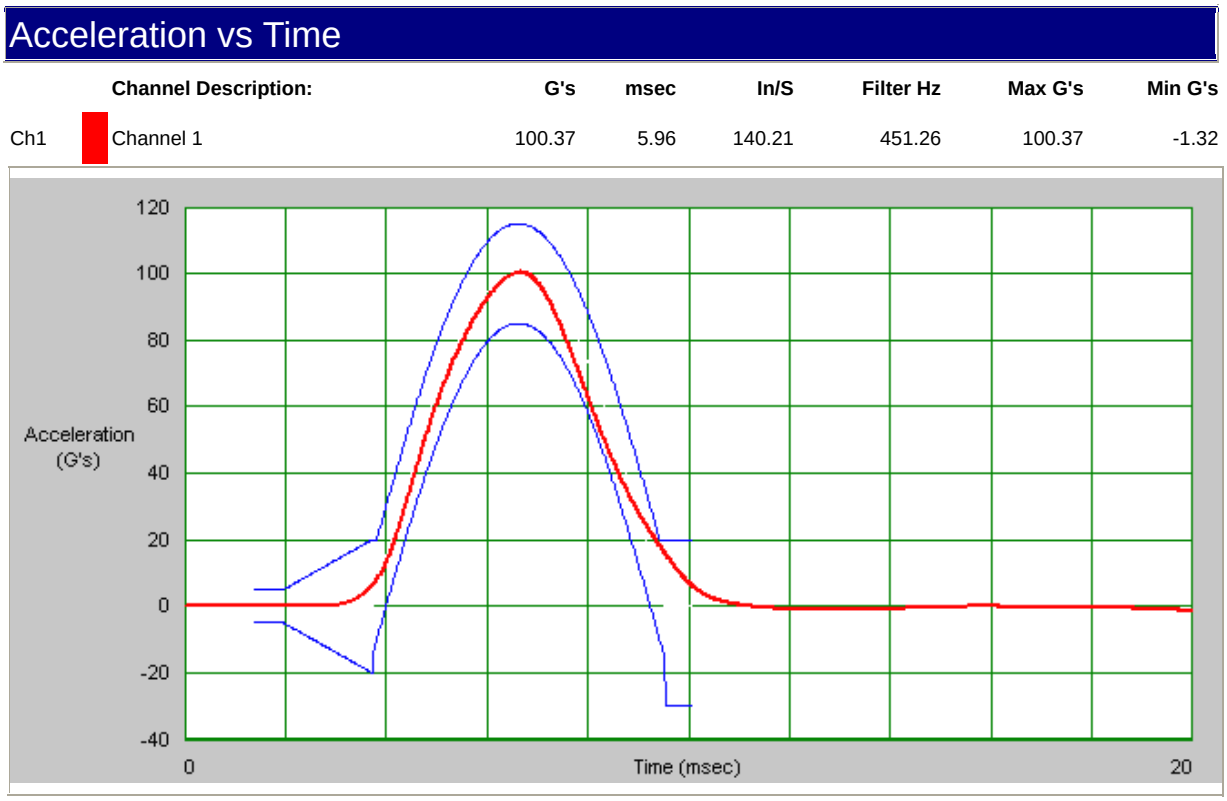
Axis +Z

Axis -Z

Test Photo:

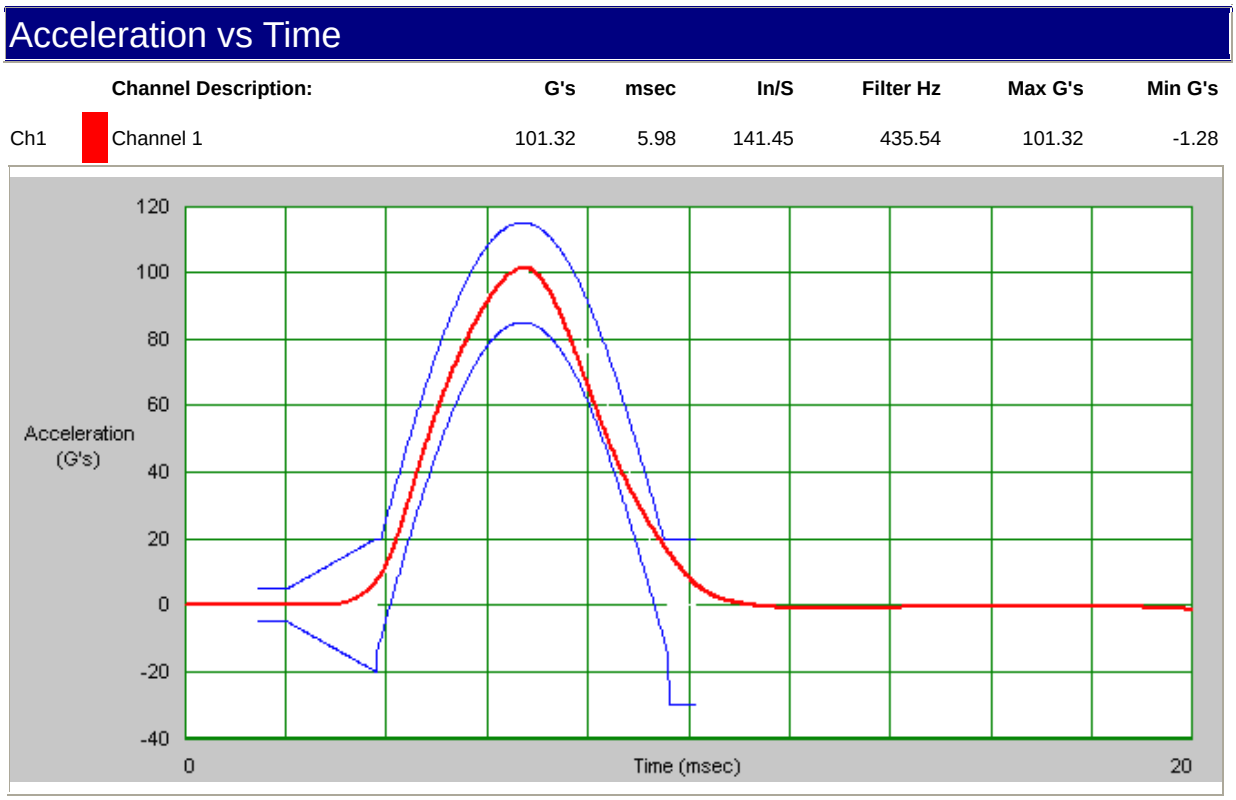
Monitor during the test

Test Curve:



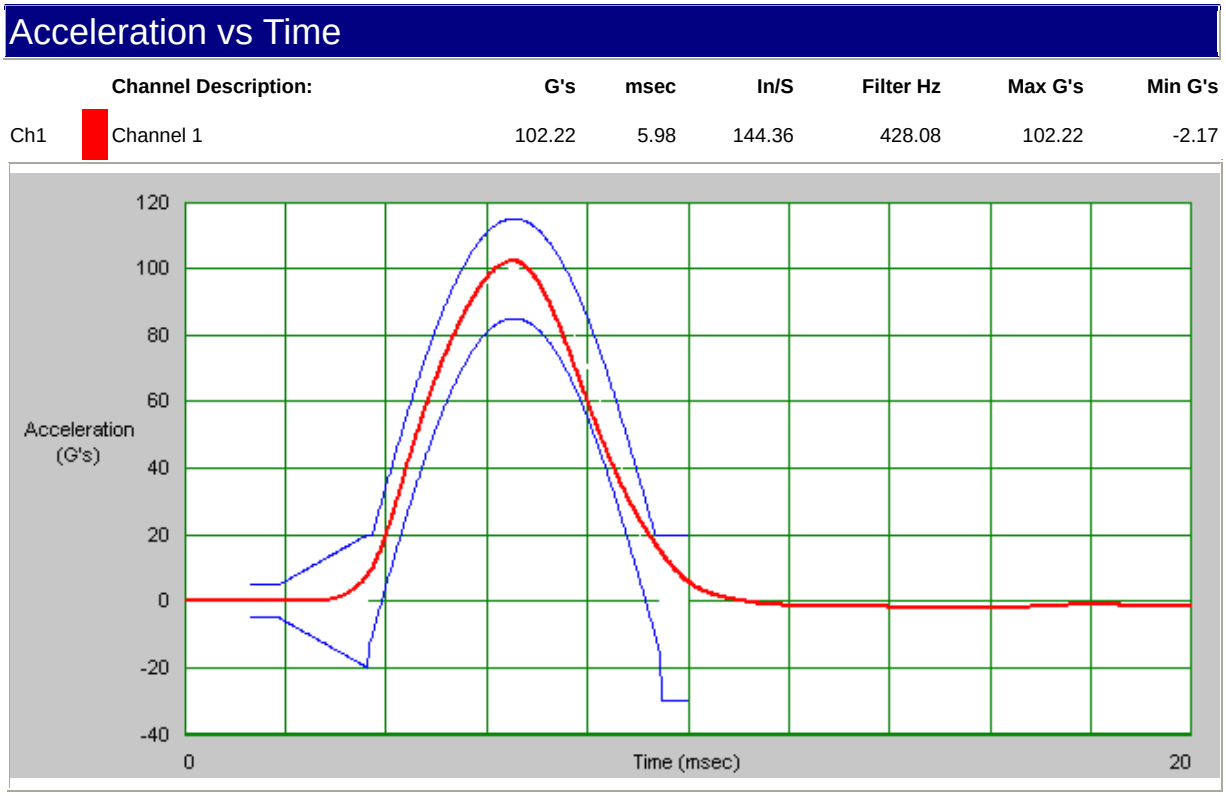
Axis +X

Test Curve:



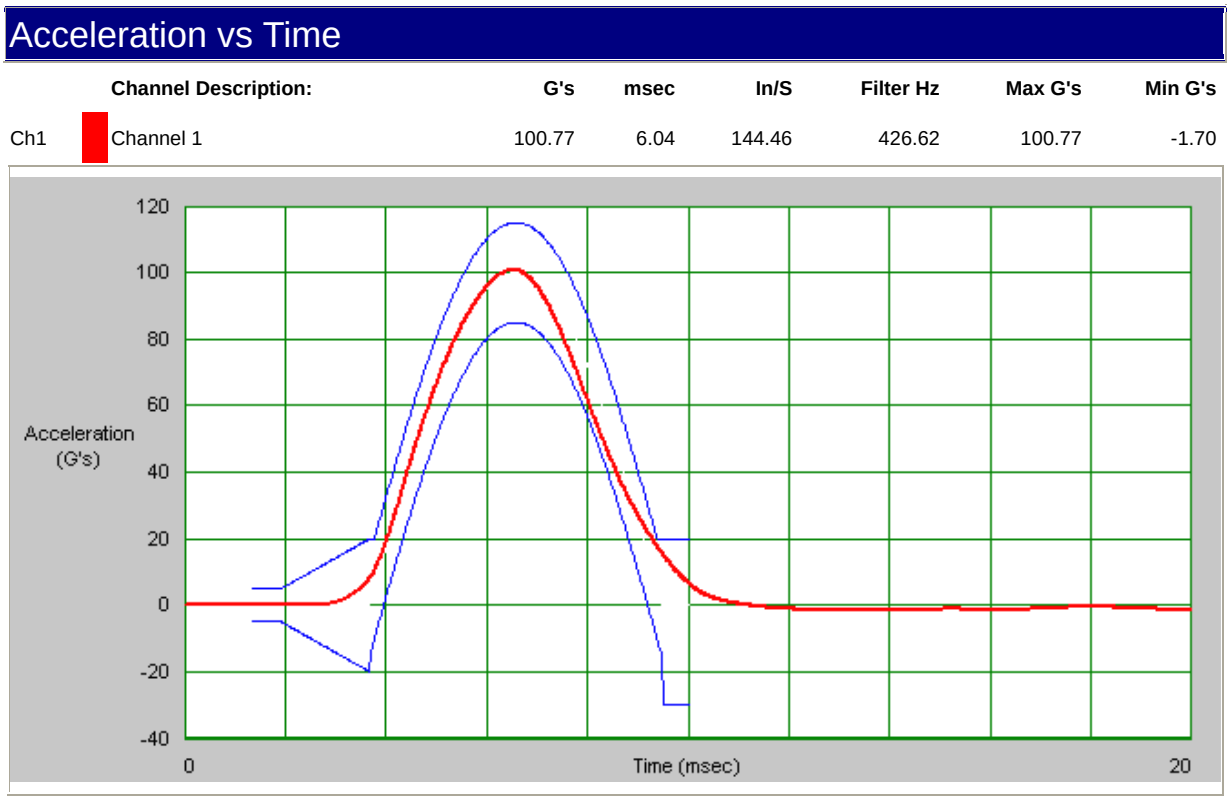
Axis -X

Test Curve:



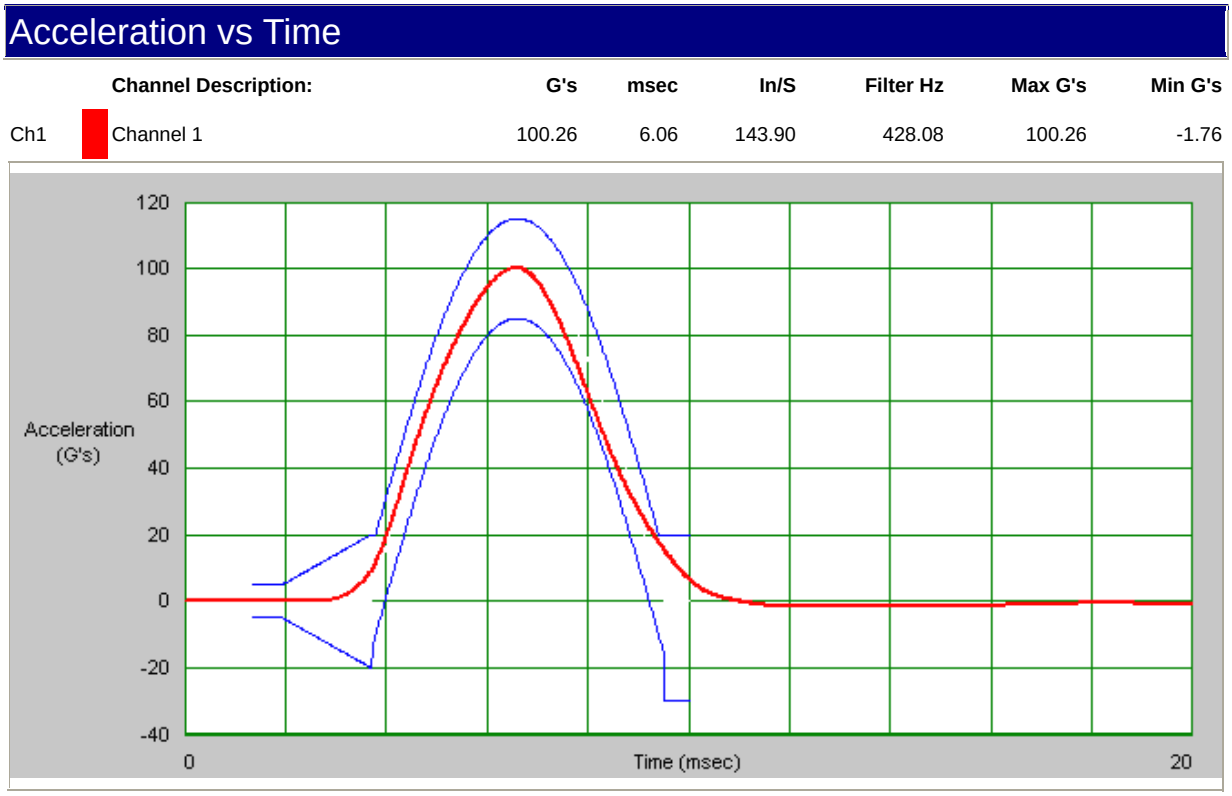
Axis +Y

Test Curve:



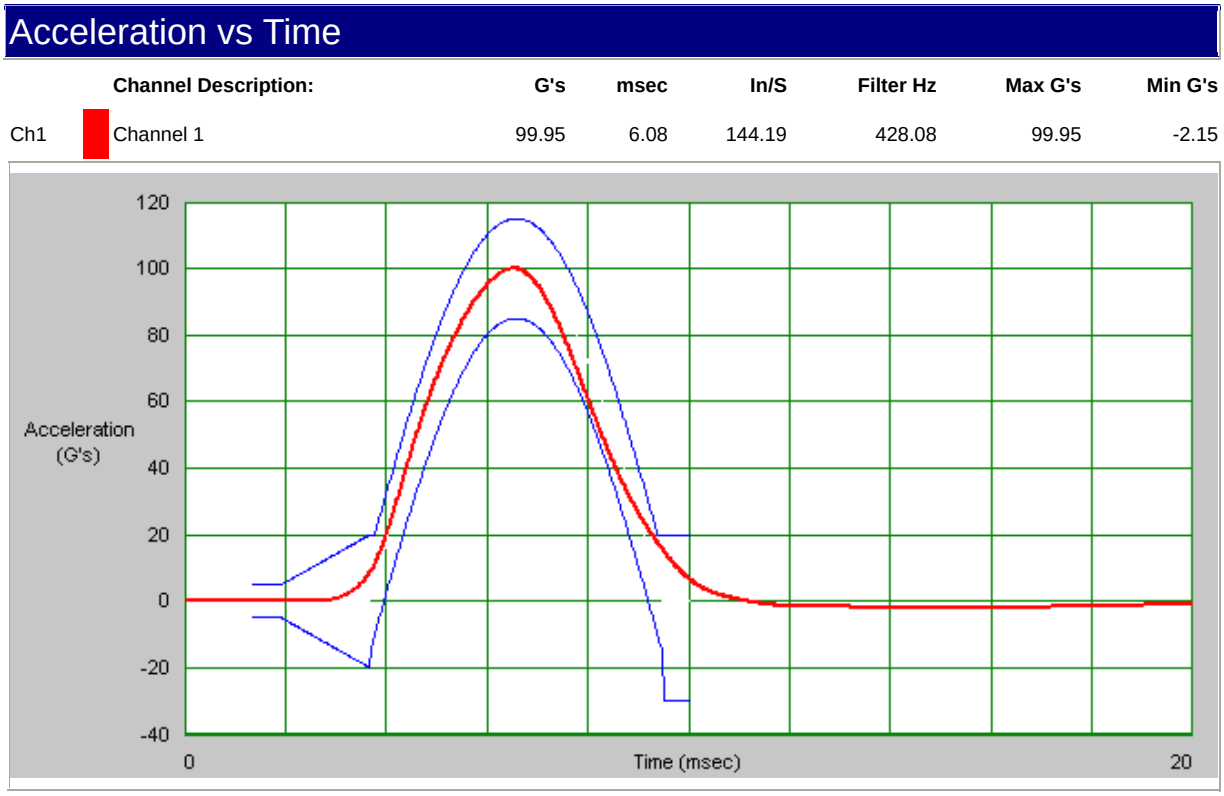
Axis -Y

Test Curve:



Axis +Z

Test Curve:



Axis -Z

Test Seq. (d):

Test Item 2: Random Vibration Test

(1) Test Equipment:

Name	Model	Serial No.	Valid Date to
Vibration Test System	LDS V850-440-LPT 750	ATTEELSZ20020	Mar. 18, 2011
Instantaneous circuit tester	NM11A	BTTEELSZ20063	Aug. 24, 2011

(2) Environmental Conditions:

Temperature: 24℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-28E-2006

(4) Tested Samples: PR101025117703-(009~012)

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

Frequency (Hz)	PSD (g^2/ Hz)	Slope (dB/oct)
50	/	+6
100-1000	0.04	/
2000	/	-6

---Acceleration: 7.56Grms

---Direction: Axis X, Y, Z

---Test duration: 2hours/axis

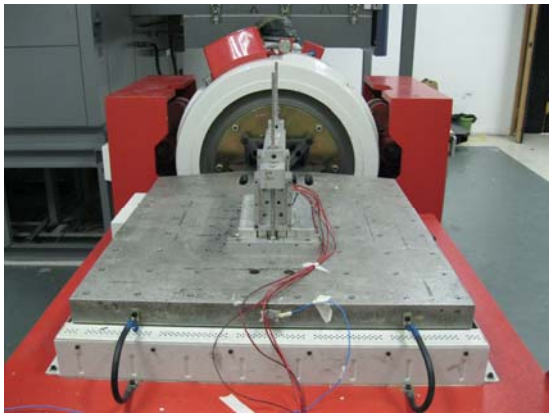
(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples.

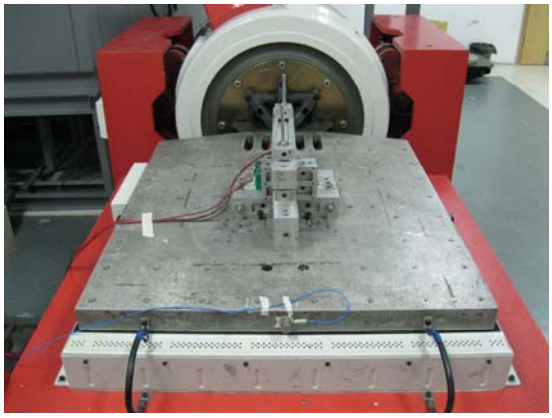
---There shall be no low microsecond event detected greater than 1 microsecond.

Test Results: After the test, there was no evidence of physical damage to the tested samples and the low microsecond event detected was never greater than 1 microsecond. Other characteristics should be evaluated by the client.

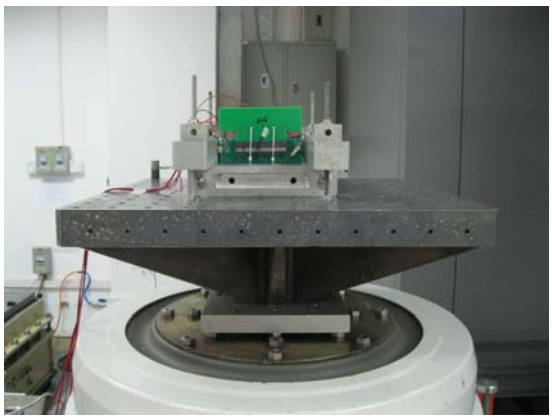
Test Photos:



Axis X



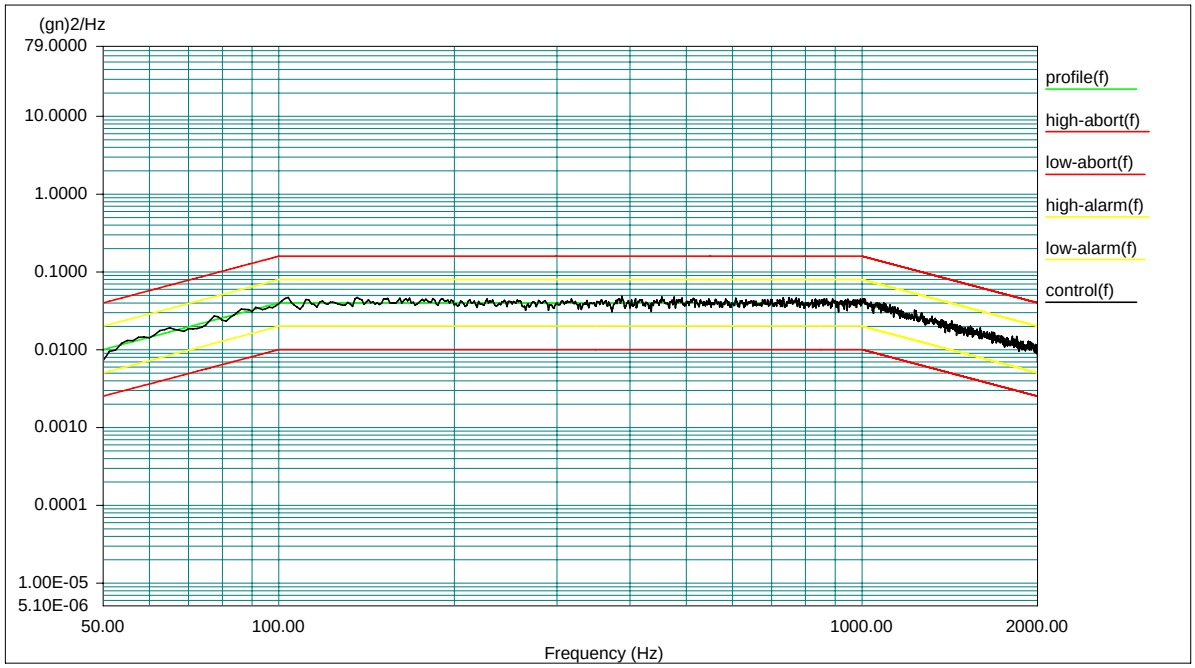
Axis Y



Axis Z

monitor during the test

Test Curve:



Level: 100 %

Control RMS: 7.570440 gn Full Level Elapsed Time: 02:00:00 Lines: 1600 Frame Time: 0.800000 Seconds

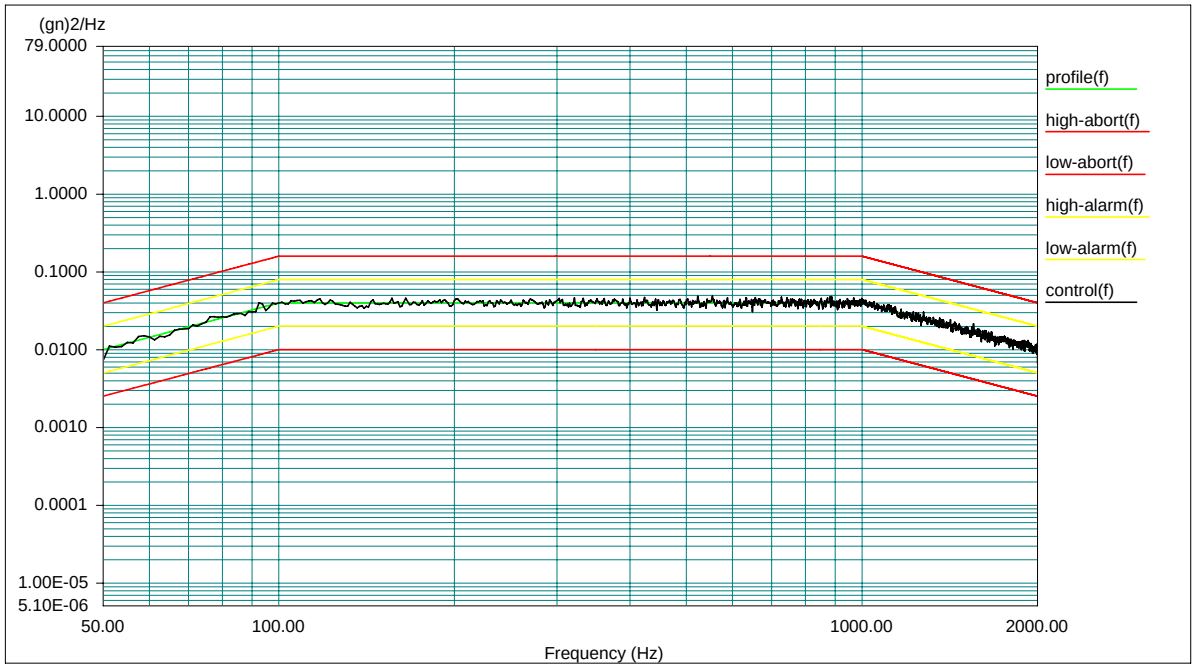
Demand RMS: 7.564273 gn Remaining Time: 00:00:00 DOF: 154 dF: 1.250000 Hz

Data saved at 11:37:35 PM, Tuesday, November 02, 2010

Report created at 11:37:39 PM, Tuesday, November 2, 2010

Axis X

Test Curve:



Level: 100 %

Control RMS: 7.575070 gn Full Level Elapsed Time: 02:00:00 Lines: 1600 Frame Time: 0.800000 Seconds

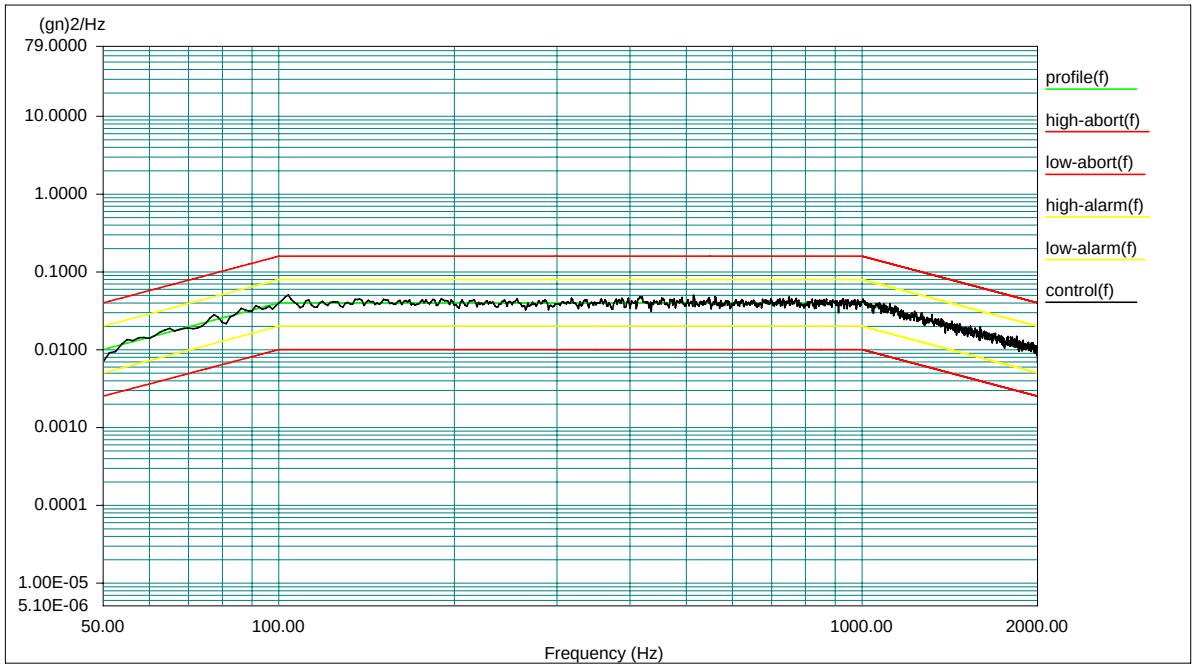
Demand RMS: 7.564273 gn Remaining Time: 00:00:00 DOF: 154 dF: 1.250000 Hz

Data saved at 02:01:30 AM, Wednesday, November 03, 2010

Report created at 02:01:32 AM, Wednesday, November 3, 2010

Axis Y

Test Curve:



Level: 100 %

Control RMS: 7.571911 gn Full Level Elapsed Time: 02:00:00 Lines: 1600 Frame Time: 0.800000 Seconds

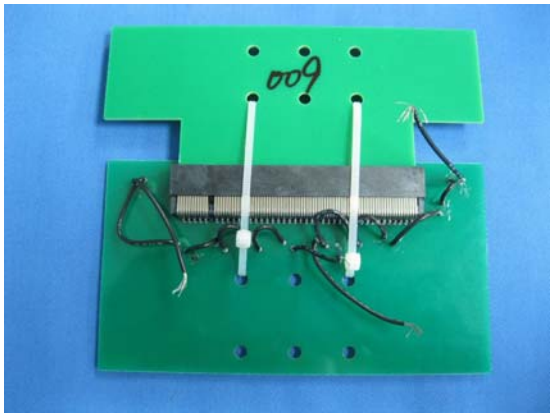
Demand RMS: 7.564273 gn Remaining Time: 00:00:00 DOF: 154 dF: 1.250000 Hz

Data saved at 07:47:30 PM, Monday, November 01, 2010

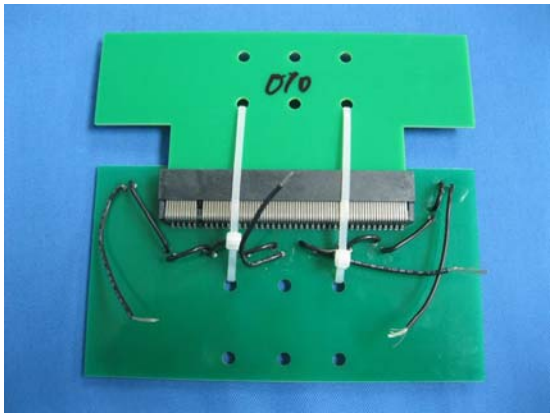
Report created at 07:47:35 PM, Monday, November 1, 2010

Axis Z

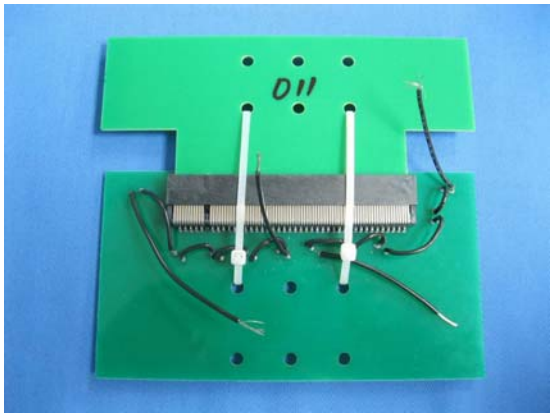
Sample Photos after Testing Seq. (d):



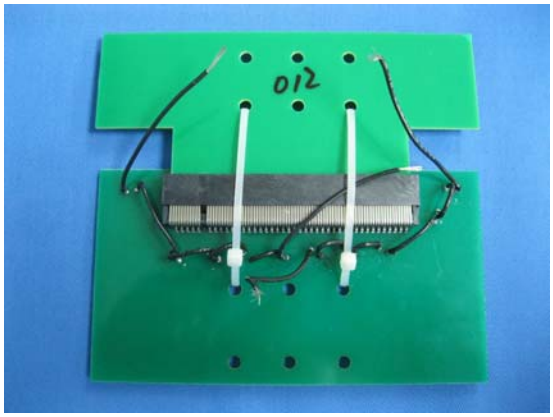
009



010



011



012

Appendix: Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
001	pin1	18.72	19.36	0.64	19.72	1.00
	pin2	18.50	18.45	-0.05	18.53	0.03
	pin3	17.75	17.88	0.13	17.86	0.11
	pin4	18.71	18.91	0.20	18.99	0.28
	pin5	17.95	18.17	0.22	18.38	0.43
	pin6	18.59	18.36	-0.23	18.50	-0.09
	pin7	19.23	19.62	0.39	18.52	-0.71
	pin8	26.35	25.80	-0.55	25.51	-0.84
	pin9	25.86	26.15	0.29	26.11	0.25
	pin10	26.00	25.81	-0.19	25.68	-0.32
	pin11	25.67	25.57	-0.10	25.58	-0.09
	pin12	26.19	25.66	-0.53	26.61	0.42
	pin13	26.18	25.90	-0.28	25.70	-0.48
	pin14	25.71	25.28	-0.43	25.73	0.02
	pin15	25.33	25.27	-0.06	27.91	2.58
	pin16	25.80	25.23	-0.57	27.31	1.51
	pin17	26.25	25.82	-0.43	25.56	-0.69
	pin18	26.16	26.08	-0.08	25.53	-0.63
	pin19	18.58	18.79	0.21	18.16	-0.42
	pin20	17.91	18.63	0.72	17.53	-0.38
	pin21	19.16	19.06	-0.10	19.09	-0.07
	pin22	18.52	18.55	0.03	18.96	0.44
	pin23	18.96	18.78	-0.18	18.55	-0.41
	pin24	18.66	18.27	-0.39	17.93	-0.73
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
002	pin1	18.71	18.32	-0.39	18.22	-0.49
	pin2	19.87	19.50	-0.37	19.06	-0.81
	pin3	18.51	18.33	-0.18	18.05	-0.46
	pin4	19.33	18.77	-0.56	18.19	-1.14
	pin5	19.02	19.15	0.13	17.83	-1.19
	pin6	18.68	18.51	-0.17	17.95	-0.73
	pin7	19.59	18.59	-1.00	18.19	-1.40
	pin8	25.23	26.12	0.89	24.51	-0.72
	pin9	25.67	25.83	0.16	25.06	-0.61
	pin10	25.12	25.26	0.14	25.12	0.00
	pin11	25.98	26.07	0.09	25.38	-0.60
	pin12	25.30	25.51	0.21	25.17	-0.13
	pin13	25.11	25.28	0.17	24.76	-0.35
	pin14	25.65	25.26	-0.39	24.69	-0.96
	pin15	25.38	25.61	0.23	24.82	-0.56
	pin16	25.51	25.12	-0.39	24.65	-0.86
	pin17	25.77	24.76	-1.01	24.38	-1.39
	pin18	25.56	24.73	-0.83	24.33	-1.23
	pin19	20.68	19.38	-1.30	18.28	-2.40
	pin20	18.36	19.79	1.43	17.37	-0.99
	pin21	19.02	18.71	-0.31	18.20	-0.82
	pin22	19.92	18.65	-1.27	18.25	-1.67
	pin23	19.65	19.01	-0.64	18.78	-0.87
	pin24	18.55	18.13	-0.42	17.80	-0.75
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
003	pin1	18.88	18.39	-0.49	18.39	-0.49
	pin2	18.81	18.66	-0.15	18.52	-0.29
	pin3	18.71	18.05	-0.66	18.22	-0.49
	pin4	18.66	18.42	-0.24	18.50	-0.16
	pin5	19.16	18.52	-0.64	18.06	-1.10
	pin6	19.18	19.11	-0.07	18.26	-0.92
	pin7	26.06	19.23	-6.83	18.03	-8.03
	pin8	25.69	25.56	-0.13	25.55	-0.14
	pin9	25.93	26.66	0.73	25.95	0.02
	pin10	25.88	25.52	-0.36	25.22	-0.66
	pin11	25.86	26.15	0.29	25.63	-0.23
	pin12	25.62	25.97	0.35	25.31	-0.31
	pin13	26.28	26.02	-0.26	25.81	-0.47
	pin14	25.67	26.23	0.56	25.89	0.22
	pin15	25.66	25.43	-0.23	25.48	-0.18
	pin16	25.21	25.59	0.38	25.38	0.17
	pin17	25.60	25.71	0.11	25.26	-0.34
	pin18	23.89	25.30	1.41	26.60	2.71
	pin19	18.26	19.13	0.87	18.99	0.73
	pin20	18.88	17.99	-0.89	18.19	-0.69
	pin21	18.63	18.70	0.07	21.80	3.17
	pin22	18.63	17.91	-0.72	18.98	0.35
	pin23	17.78	17.75	-0.03	17.89	0.11
	pin24	17.68	17.66	-0.02	18.05	0.37
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
004	pin1	19.23	19.29	0.06	18.63	-0.60
	pin2	18.80	18.87	0.07	18.69	-0.11
	pin3	18.61	18.81	0.20	18.66	0.05
	pin4	18.38	18.38	0.00	18.47	0.09
	pin5	18.91	18.53	-0.38	18.39	-0.52
	pin6	18.81	18.62	-0.19	18.28	-0.53
	pin7	18.98	18.93	-0.05	18.71	-0.27
	pin8	25.56	25.68	0.12	28.35	2.79
	pin9	25.88	25.53	-0.35	25.32	-0.56
	pin10	25.35	25.32	-0.03	25.08	-0.27
	pin11	26.23	26.32	0.09	26.02	-0.21
	pin12	25.72	25.50	-0.22	25.39	-0.33
	pin13	25.51	25.69	0.18	25.36	-0.15
	pin14	25.32	25.70	0.38	25.56	0.24
	pin15	25.16	26.12	0.96	26.07	0.91
	pin16	25.83	25.83	0.00	25.61	-0.22
	pin17	26.36	25.52	-0.84	25.17	-1.19
	pin18	25.38	25.12	-0.26	28.91	3.53
	pin19	20.18	19.58	-0.60	25.26	5.08
	pin20	19.20	18.25	-0.95	20.37	1.17
	pin21	19.38	18.80	-0.58	19.60	0.22
	pin22	18.61	18.01	-0.60	18.31	-0.30
	pin23	18.52	18.62	0.10	18.69	0.17
	pin24	19.07	18.77	-0.30	19.12	0.05
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
005	pin1	19.08	18.39	-0.69	18.53	-0.55
	pin2	18.55	18.65	0.10	19.26	0.71
	pin3	18.39	18.13	-0.26	18.18	-0.21
	pin4	18.86	18.52	-0.34	18.51	-0.35
	pin5	18.22	18.57	0.35	18.77	0.55
	pin6	19.60	18.26	-1.34	18.43	-1.17
	pin7	20.38	18.38	-2.00	18.32	-2.06
	pin8	25.88	25.21	-0.67	25.83	-0.05
	pin9	25.15	25.86	0.71	26.16	1.01
	pin10	25.66	25.25	-0.41	25.53	-0.13
	pin11	25.87	25.83	-0.04	26.03	0.16
	pin12	26.59	25.52	-1.07	25.78	-0.81
	pin13	25.56	25.13	-0.43	25.53	-0.03
	pin14	26.08	25.52	-0.56	25.86	-0.22
	pin15	26.66	25.16	-1.50	25.38	-1.28
	pin16	25.76	25.39	-0.37	25.35	-0.41
	pin17	26.03	25.78	-0.25	25.33	-0.70
	pin18	25.80	23.96	-1.84	25.61	-0.19
	pin19	20.12	29.56	9.44	20.09	-1.24
	pin20	19.20	17.97	-1.23	18.88	0.69
	pin21	19.96	17.52	-2.44	19.89	-1.15
	pin22	18.53	18.36	-0.17	18.81	1.09
	pin23	18.36	19.26	0.90	19.62	0.90
	pin24	18.91	19.71	0.80	19.26	0.35
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
006	pin1	18.22	18.95	0.73	20.10	1.88
	pin2	18.61	18.36	-0.25	18.91	0.30
	pin3	18.60	18.71	0.11	18.30	-0.30
	pin4	18.16	19.91	1.75	18.90	0.74
	pin5	18.35	18.21	-0.14	18.88	0.53
	pin6	18.69	19.18	0.49	20.05	1.36
	pin7	19.11	20.02	0.91	20.69	1.58
	pin8	25.16	25.98	0.82	26.76	1.60
	pin9	26.36	26.29	-0.07	27.36	1.00
	pin10	26.83	26.08	-0.75	26.17	-0.66
	pin11	25.59	26.30	0.71	28.81	3.22
	pin12	25.89	26.90	1.01	27.02	1.13
	pin13	26.76	25.82	-0.94	26.33	-0.43
	pin14	26.08	26.23	0.15	30.68	4.60
	pin15	26.21	26.55	0.34	26.61	0.40
	pin16	25.73	25.57	-0.16	25.72	-0.01
	pin17	26.23	25.78	-0.45	26.10	-0.13
	pin18	25.40	25.71	0.31	26.90	1.50
	pin19	18.63	19.73	1.50	23.80	5.57
	pin20	18.23	18.86	-0.72	20.86	1.28
	pin21	19.58	20.20	1.43	19.50	0.73
	pin22	18.77	18.51	-0.77	18.66	-0.62
	pin23	19.28	18.76	0.10	18.90	0.81
	pin24	18.09	18.86	0.77	19.10	1.01
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
007	pin1	19.39	18.39	-1.00	18.33	-1.06
	pin2	18.42	18.95	0.53	18.53	0.11
	pin3	18.55	18.46	-0.09	18.20	-0.35
	pin4	18.68	18.13	-0.55	18.08	-0.60
	pin5	18.75	17.66	-1.09	17.52	-1.23
	pin6	19.51	18.76	-0.75	19.26	-0.25
	pin7	19.69	18.78	-0.91	18.29	-1.40
	pin8	26.31	25.62	-0.69	25.16	-1.15
	pin9	26.05	26.91	0.86	26.37	0.32
	pin10	25.55	25.58	0.03	25.70	0.15
	pin11	26.07	26.77	0.70	26.37	0.30
	pin12	26.52	25.39	-1.13	25.65	-0.87
	pin13	25.40	25.66	0.26	26.97	1.57
	pin14	26.18	26.65	0.47	28.60	2.42
	pin15	25.90	26.33	0.43	26.20	0.30
	pin16	25.66	26.22	0.56	25.79	0.13
	pin17	25.56	26.32	0.76	27.15	1.59
	pin18	19.68	25.08	5.40	26.90	7.22
	pin19	19.26	19.16	-0.10	20.58	1.32
	pin20	19.09	18.15	-0.94	18.13	-0.96
	pin21	18.26	19.81	1.55	19.40	1.14
	pin22	18.61	18.77	0.16	18.96	0.35
	pin23	18.56	19.30	0.74	19.05	0.49
	pin24	19.90	18.51	-1.39	18.03	-1.87
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

Appendix (Cont.): Data of the contact resistance after Testing Seq. (c)

Sample No.	Pin No.	LLCR(mΩ)				
		initial	after shock test	ΔR1	after vibration test	ΔR2
008	pin1	18.52	18.56	0.04	17.81	0.71
	pin2	18.56	19.21	0.65	18.39	0.17
	pin3	15.56	18.65	3.09	17.71	2.15
	pin4	18.39	18.27	0.12	18.09	0.30
	pin5	18.51	17.88	0.63	18.02	0.49
	pin6	19.09	18.95	0.14	18.21	0.88
	pin7	18.89	19.06	0.17	17.58	1.31
	pin8	25.10	25.25	0.15	24.56	0.54
	pin9	26.07	25.97	0.10	25.10	0.97
	pin10	25.65	25.68	0.03	25.03	0.62
	pin11	26.66	26.37	0.29	25.60	1.06
	pin12	25.38	26.00	0.62	25.51	0.13
	pin13	25.73	26.05	0.32	25.01	0.72
	pin14	26.51	27.17	0.66	25.37	1.14
	pin15	26.08	26.21	0.13	25.09	0.99
	pin16	26.17	26.07	0.10	26.13	0.04
	pin17	25.20	26.33	1.13	25.22	0.02
	pin18	25.18	25.13	0.05	25.03	0.15
	pin19	19.79	19.12	0.67	18.39	1.40
	pin20	18.51	18.08	0.43	18.17	0.34
	pin21	19.71	19.66	0.05	18.33	1.38
	pin22	18.99	18.83	0.16	17.76	1.23
	pin23	18.80	19.23	0.43	18.15	0.65
	pin24	19.85	18.53	1.32	17.92	1.93
ΔR1=R(after shock test)- R(initial)						
ΔR2=R(after vibration test)- R(initial)						

*** End of report ***